

In the specification:

Please replace paragraph starting on page 6, line 8 and ending on line 17 with the following paragraph.

The lid assembly 16 includes a lid 23 and a pressure plate 44. When the lid assembly 16 is closed onto base 14, surface 43 on pressure plate 44 is positioned over surface 112 on base bottom 114. In addition, surface ~~[[45]]~~ 43 on pressure plate 44 is positioned over test socket 40. If an integrated circuit is positioned over the test socket 40, surface ~~[[45]]~~ 43 is positioned to contact the integrated circuit and provide an even pressure to bring the integrated circuit into contact with the socket body in the test socket 40.

Please replace paragraph starting on page 8, line 26 and ending on page 9, line 10 with the following paragraph.

The locking mechanism for the cam ratchet head allows the pressure plate to be held in a fixed position during a test process. The locking mechanism of the teeth within the cam ratchet head allows incremental lowering or raising of the pressure plate (for example in 0.088 inch increments), as the cam ratchet head rotates. The cam groove within the cam ratchet head creates a relationship between the rotational movement of the cam ratchet head and the vertical movement of the pressure plate (for example with every 1 degree of rotational travel of the cam ratchet head the pressure plate moves by 0.0005 inch increments in a vertical direction). In an automated process, bars 66 and 88 may be robotically engaged. For testing of leadless ICs or integrated circuits with varying package thickness, bar 66 may be only partially raised so that the pressure plate is only

raised slightly. For testing integrated circuits with pins, bar 66 may be fully raised as shown in ~~Fig. 11a~~ Fig. 2a when the integrated circuit 12 is inserted. During testing, bar 66 may be partially or fully lowered.